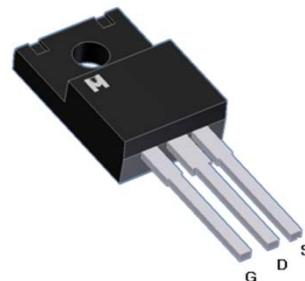
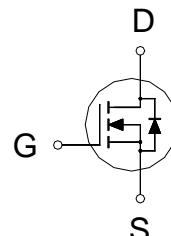


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV <sub>DSS</sub>	600V
R <sub>DSON</sub> (MAX.)	2.5Ω
I <sub>D</sub>	4A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±30	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	4	A
	T <sub>C</sub> = 100 °C		2.5	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	16	
Avalanche Current		I <sub>AS</sub>	3	
Avalanche Energy	L = 3mH, I <sub>D</sub> =3A, R <sub>G</sub> =25Ω	E <sub>AS</sub>	13.5	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 0.5mH	E <sub>AR</sub>	2.25	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	48	W
	T <sub>C</sub> = 100 °C		19	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	2.6	2.6	°C / W
Junction-to-Ambient	R <sub>θJA</sub>		60	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	600			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2	3	5	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 30V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 600V, V_{GS} = 0V$			10	$\mu\text{A}$
		$V_{DS} = 480V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 2A$		2.1	2.5	$\Omega$
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 25V, I_D = 2A$		2		S
DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$		455		pF
Output Capacitance	$C_{oss}$			49		
Reverse Transfer Capacitance	$C_{rss}$			2.9		
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 300V, V_{GS} = 10V, I_D = 1A$		8.4		nC
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			2.2		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			2.2		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	$V_{DS} = 300V, I_D = 1.5A, V_{GS} = 10V, R_G = 20\Omega$		20		nS
Rise Time <sup>1,2</sup>	$t_r$			30		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$			20		
Fall Time <sup>1,2</sup>	$t_f$			30		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ )						
Continuous Current	$I_S$				4	A
Pulsed Current <sup>3</sup>	$I_{SM}$				16	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.4	V
Reverse Recovery Time	$t_{rr}$	$I_F = I_S, dI_F/dt = 100A/\mu\text{s}$		0.3		$\mu\text{s}$
Reverse Recovery Charge	$Q_{rr}$				1.0	$\mu\text{C}$

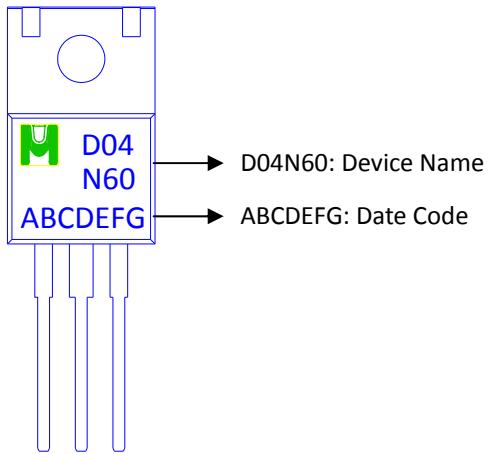
<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

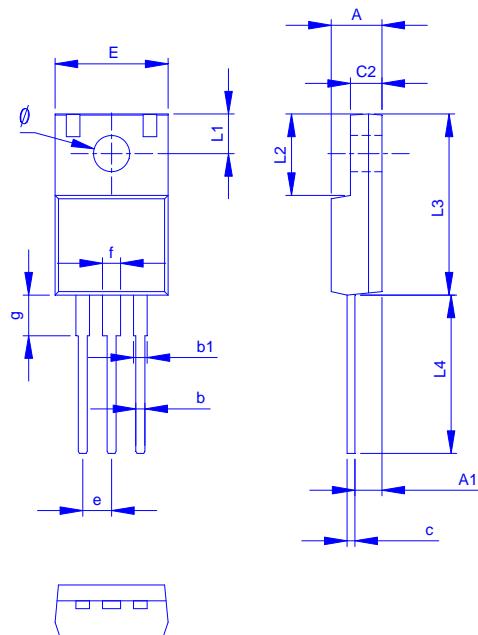
<sup>3</sup>Pulse width limited by maximum junction temperature.

### Ordering & Marking Information:

Device Name: EMD04N60F for TO-220F



### Outline Drawing



Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L1	L2	L3	L4	Ø	e	f	g
Min.	4.20	1.95	0.50	0.90	0.45	2.34	9.70	2.70	6.48	14.80	12.68	3.00	2.35	1.18	3.13
Max.	4.90	2.96	1.05	1.50	0.80	3.20	10.66	3.80	7.50	16.30	14.50	3.50	2.75	1.90	4.00

## TYPICAL CHARACTERISTICS

